

Notice of References Cited	Application/Control No. 09/977,994		Applicant(s)/Patent Under Reexamination NAGATA ET AL.	
	Examiner Jeffrey R. West		Art Unit 2857	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0022951	02-2002	Heijningen et al.	703/16
*	B	US-6,144,217	11-2000	Iwata et al.	326/27
*	C	US-4,366,456	12-1982	Ueno et al.	333/173
*	D	US-4,543,546	09-1985	Hariharan	333/173
*	E	US-5,424,670	06-1995	Samuels et al.	327/337
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	J	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	Nagata et al., "Measurements and Analyses of Substrate Noise Waveform in Mixed Signal IC Environment". Proceedings of the IEEE 1999 Custom Integrated Circuits Conference. May 1999.			
*	V	Mitra et al., "Substrate-Aware Mixed-Signal Macrocell Placement in WRIGHT". IEEE Journal of Solid-State Circuits. Vol. 30. No. 3, March 1995.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.